

Small-Angle X-ray Scattering at Large Angles in the Soft X-ray Range: Layer Discontinuity in Ultra-Short Period W/B₄C Multilayers

C. C. Walton and J. B. Kortright
Advanced Light Source and Materials Science Division
Ernest Orlando Lawrence Berkeley National Laboratory
Berkeley, California, 94720 USA

INTRODUCTION

Recent novel applications of multilayer x-ray mirrors, for example as linear polarizers in the soft x-ray,¹ have brought with them new interest in multilayers of ultra-short periods ($d < 15\text{\AA}$). Most materials combinations show a severe loss of reflectivity at periods below 30-40 \AA , but W/B₄C has been shown^{2,3} to maintain useful reflectivities (1-2% or better) for periods down to 12 \AA . To optimize performance at these periods, we have studied the microstructure of W/B₄C multilayers with Small-Angle X-ray Scattering (SAXS) experiments at Beamline 6.3.2 at ALS. Measurements usually performed at 0.1°-5° in the hard x-ray range correspond to angles up to 60° at soft x-ray energies (700eV). While not generally applied to x-ray multilayers, this technique provides valuable information on in-plane inhomogeneities not easily accessible to other techniques. Discontinuity of the films at early stages of growth contributes to reflectivity loss and can be directly measured by this technique.

EXPERIMENT

The multilayers in this study were grown by standard magnetron sputtering techniques described elsewhere, on free-standing Si₃N₄ membranes about 1500 \AA thick. There were examined in transmission at BL 6.3.2 at $E = 700\text{eV}$ and on a rotating-anode source at CuK $_{\alpha}$ ($\lambda = 1.54\text{\AA}$). The scattered signal was measured by a detector at angle 2θ , and the sample was rotated by θ to keep the scattering vector in the plane of the films. Background signal from the tails of the incident beam was measured separately and subtracted, and the remaining signal divided by the full beam intensity I_0 to yield an absolute scattered intensity vs. angle. Multilayers of period $d = 6, 14, 22$ and 30 \AA were measured.

ANALYSIS

The scattered signal was compared to a simple SAXS model based on earlier work by Rice.⁴ The model assumes spherical particles of one composition in a homogeneous matrix of another. Using the known overall multilayer composition, the size of the particles and the volume fraction they occupy were varied to fit the experimental results. Within plausible ranges of these parameters a unique fit was obtained.

RESULTS AND DISCUSSION

The experimental data (points) and fits (smooth curves) are shown in Fig. 1. For the shortest d-spacing, a broad peak is present at both incident energies. At $d = 14\text{\AA}$ a weak peak at a smaller angle (corresponding to larger particles) is present, and at $d = 22\text{\AA}$ and $d = 30\text{\AA}$ no SAXS signal is observed. This is consistent with a transition from discontinuous to continuous multilayers between $d = 14\text{\AA}$ and $D = 22\text{\AA}$. Because the scattering factor for W is more than ten times that of B or C at both wavelengths, the SAXS signal represents almost exclusively the W-W correlations. For a continuous multilayer the scattering vector lies parallel to the layers and measures only weak in-plane density fluctuations, while for a discontinuous multilayer the sizes and separations of the islands in the film give a strong in-plane signal.

The fit parameters agree well for the two incident energies used – particles of about 25Å diameter for the $d = 6\text{\AA}$ multilayer and 32Å diameter for the $d = 14\text{\AA}$ multilayer. The results are corroborated by plan-view HRTEM of other W/B₄C specimens grown under the same conditions – Fig. 2. shows a $d = 6\text{\AA}$ multilayer with a clear islanded structure. The islands are of irregular shape, consistent with a broad distribution of widths indicated by the peak width in the SAXS signal, and show diameters about 25Å.

CONCLUSIONS

W/B₄C forms layered structures with separate phases for periods as short as 6Å, though for periods below 14-22Å the layers are discontinuous. This work demonstrates that scattering measurements in the soft x-ray can probe inhomogeneities in materials on the nm scale and greater. Coupled with the strong anomalous dispersion (in charge and possibly magnetic scattering) associated with many soft x-ray core levels, this capability can be readily extended to study a variety of materials and problems.

REFERENCES

1. J. B. Kortright, M. Rice, and R. Carr, "Soft-X-ray Faraday rotation at Fe L_{2,3} edges," *Physical Review B (Condensed Matter)* **51** (15), 10240-3 (1995).
2. J. F. Seely, G. Gutman, J. Wood *et al.*, "Normal-incidence reflectance of W/B₄C multilayer mirrors in the 34-50Å wavelength region," *Applied Optics* **32** (19), 3541-3 (1993).
3. C.C. Walton and J.B. Kortright, to be published.
4. M. B. Rice, "Anomalous Small Angle X-Ray Scattering Studies of Amorphous Metal-Germanium Alloys," Ph.D., Stanford University, 1993.

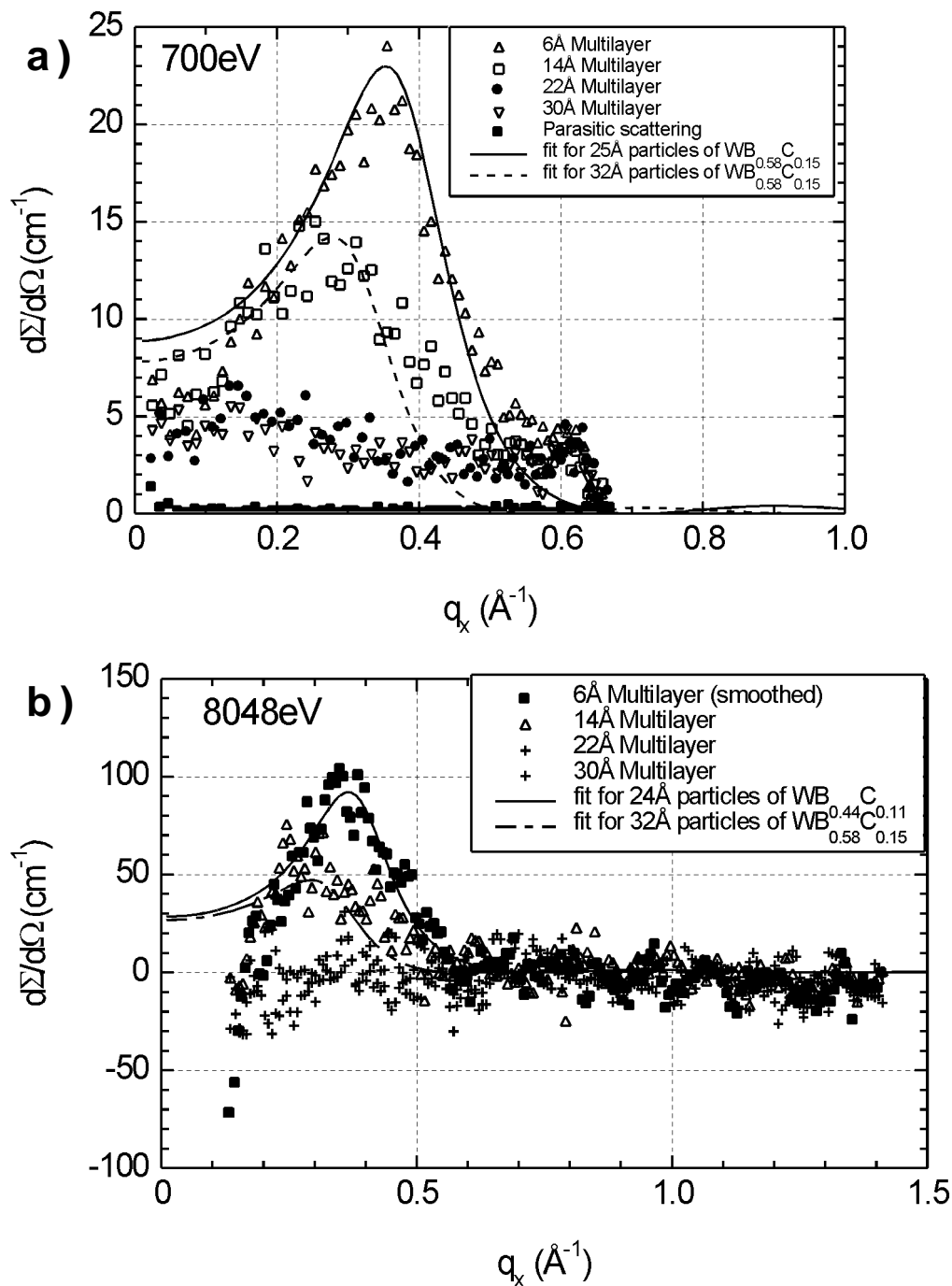


Fig. 1. *a)* Small-Angle X-Ray Scattering (SAXS) data (points) and fits (smooth curves) for W/B₄C multilayers of four periods, taken at $E = 700\text{eV}$. Fits are consistent with the W-rich layers in the shortest-period multilayers (6Å and 14Å) consisting of islands of about 24Å and 32Å diameter rather than continuous layers. The islands are not bulk W but compounds near the composition W₂B. *b)* Similar results taken at $E = 8048\text{eV}$ (CuK_α).

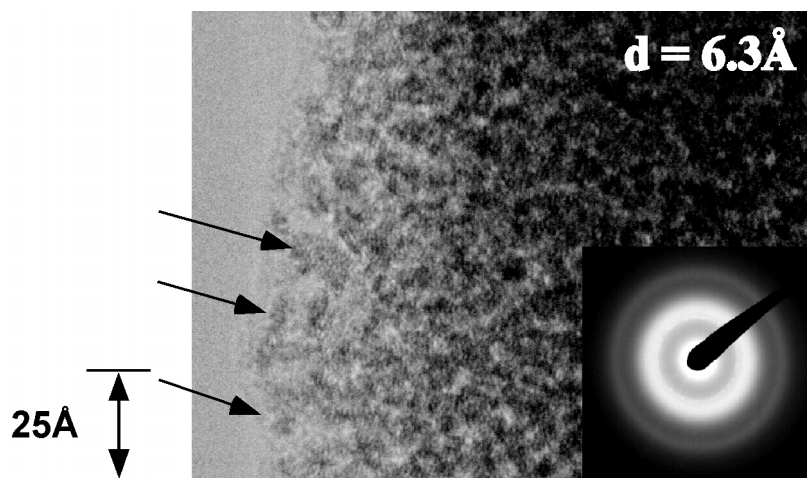


Fig. 2. Plan-view HRTEM of $d = 6.3 \text{ \AA}$ W/B₄C multilayer. Island structure of W-rich layers is clearly visible.

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Author Affiliations:

Contact author: CCW now at Advanced Microtechnology Program, L-395, Lawrence Livermore National Laboratory, Livermore, CA 94550 USA. e-mail walton9@llnl.gov, phone 510-423-2834.

Principal investigator when experiments were done: JBK at Materials Science Division, MS 2-100, Lawrence Berkeley National Laboratory, Berkeley, CA 94720. e-mail jbkortright@lbl.gov, phone 510-486-5960.